

# **KLC310FL01WW**

## **Technical Data**



**Aug. 3rd, 2023**

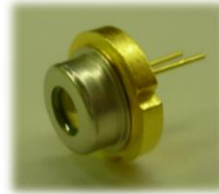
Laser & GaN Technology Business Group  
Nuvoton Technology Corporation Japan

- **Specification**
- **Outline, Pin connection**
- **Technical data**
  - **L-I, V-I**
  - **Wavelength**
  - **FFP**
  - **Aging test**
  - **ESD failure level**

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  - FFP
  - Aging test
  - ESD failure level

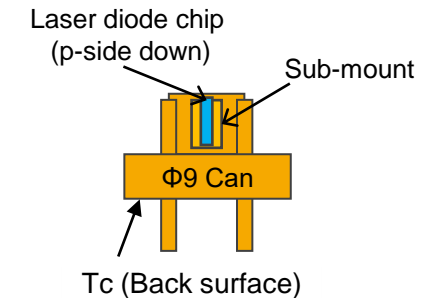
### ■ Features

- Multi transverse mode
- $\Phi 9.0\text{mm}$  TO-CAN package
- Emitter size :  $15\mu\text{m} \times 1\mu\text{m}$



### ■ Absolute maximum ratings

Item	Symbol	Value	Unit	Condition
Optical output power	$P_{max}$	600	mW	CW
Reverse voltage	$V_r$	5.0	V	
Operating temperature (Case)	$T_c$	+20 to +30	$^{\circ}\text{C}$	-
Storage temperature	$T_{stg}$	-40 to +85	$^{\circ}\text{C}$	-



### ■ Electrical and optical characteristics

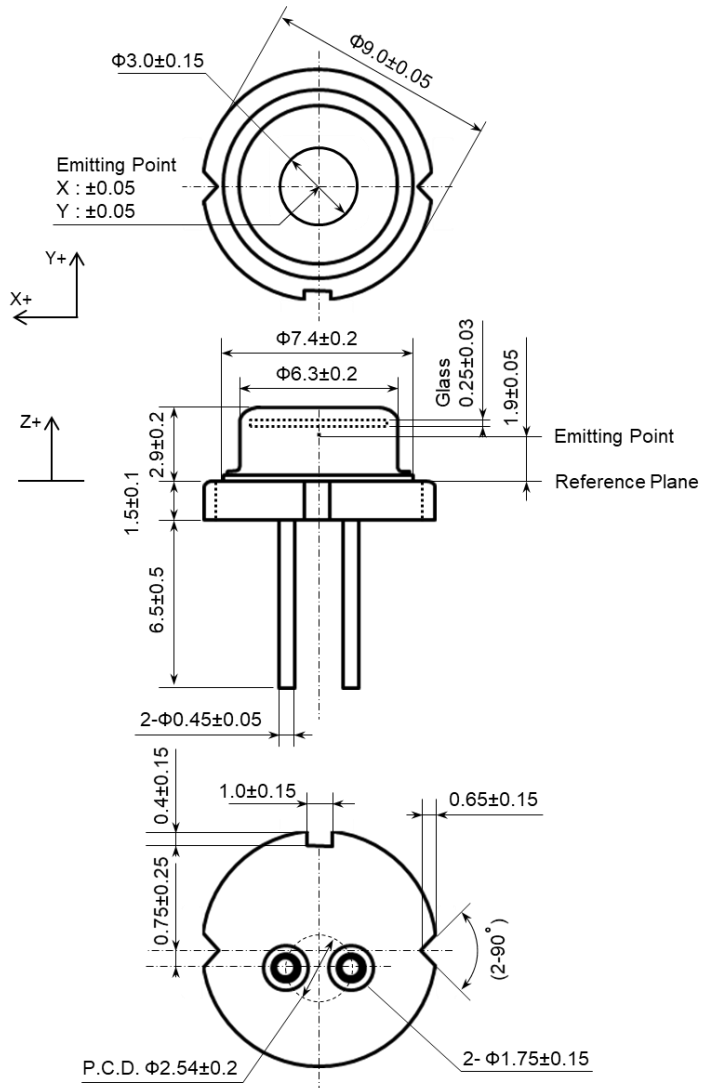
[ Conditions ] CW,  $T_c=25\pm 3\text{ }^{\circ}\text{C}$

Item	Symbol	Value			Unit	Condition	
		Min	Typ.	Max			
Threshold current	$I_{th}$	-	340	500	mA	-	
Operating current	$I_{op}$	420	620	820	mA	$P_o=500\text{mW}$	
Operating voltage	$V_{op}$	-	5.0	5.5	V	$P_o=500\text{mW}$	
Slope efficiency	$S_e$	1.3	1.8	2.4	W/A	$P_o=200\text{-}500\text{mW}$	
Peak wavelength	$\lambda$	370	378	380	nm	$P_o=500\text{mW}$	
Beam divergence <sup>1)</sup>	Parallel	$\theta_h$	10	18	28	deg.	$P_o=500\text{mW}$
	Perpendicular	$\theta_v$	32	39	46	deg.	$P_o=500\text{mW}$
Angle accuracy of beam center	Parallel	$\theta_x$	-3	-	+3	deg.	$P_o=500\text{mW}$
	Perpendicular	$\theta_y$	-3	-	+3	deg.	$P_o=500\text{mW}$

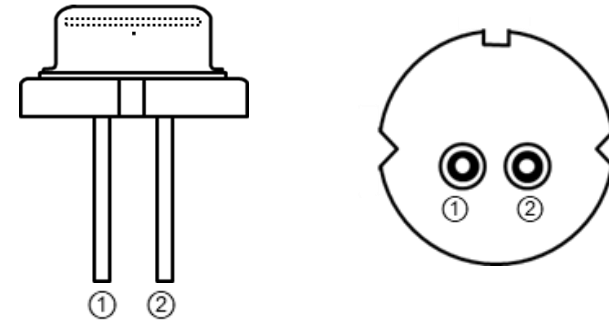
<sup>1)</sup> Full width at  $1/e^2$  of the peak intensity

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  - ESD failure level

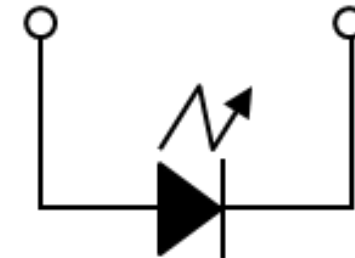
### ■ Outline



### ■ Pin connection



① (LD Anode)      ② (LD Cathode)



#### Note

1. X-Y tolerance of lead is specified on the plane of package bottom.
2. Unit: mm

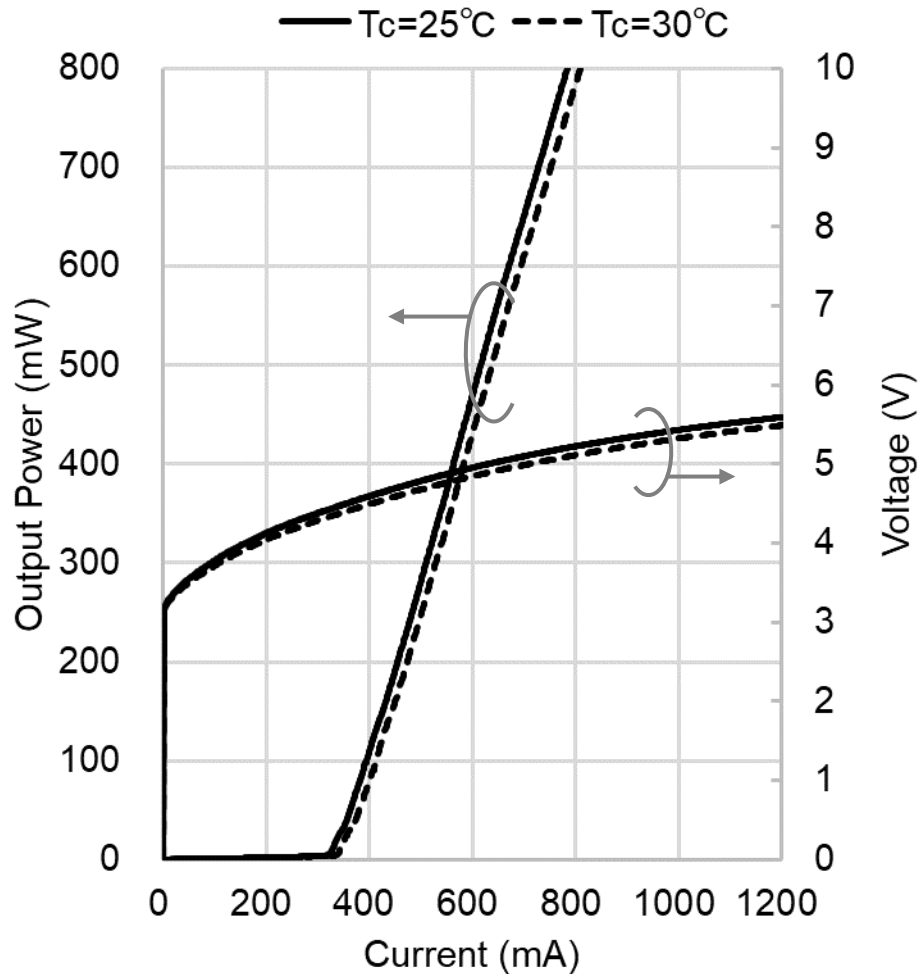
#### Projection



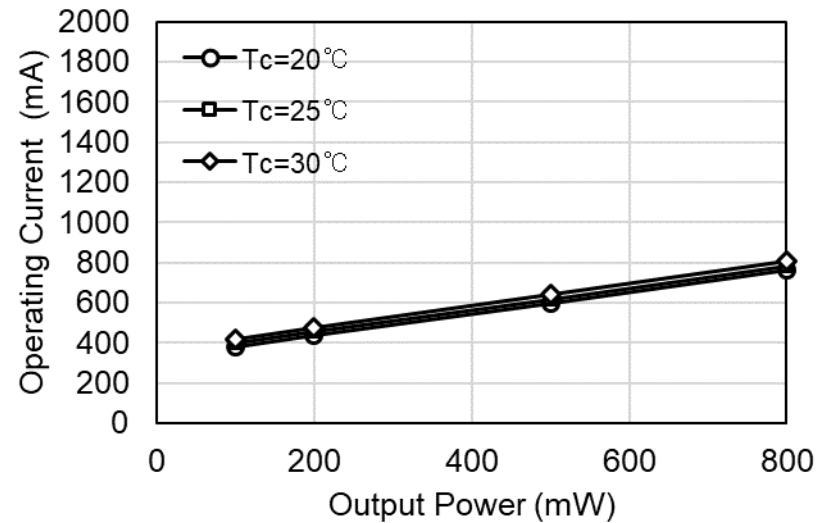
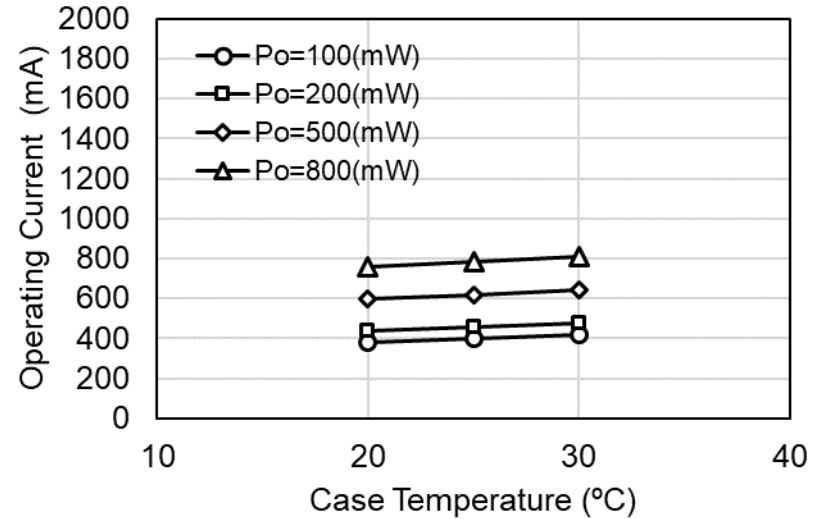
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### L-I, V-I

[Conditions] CW

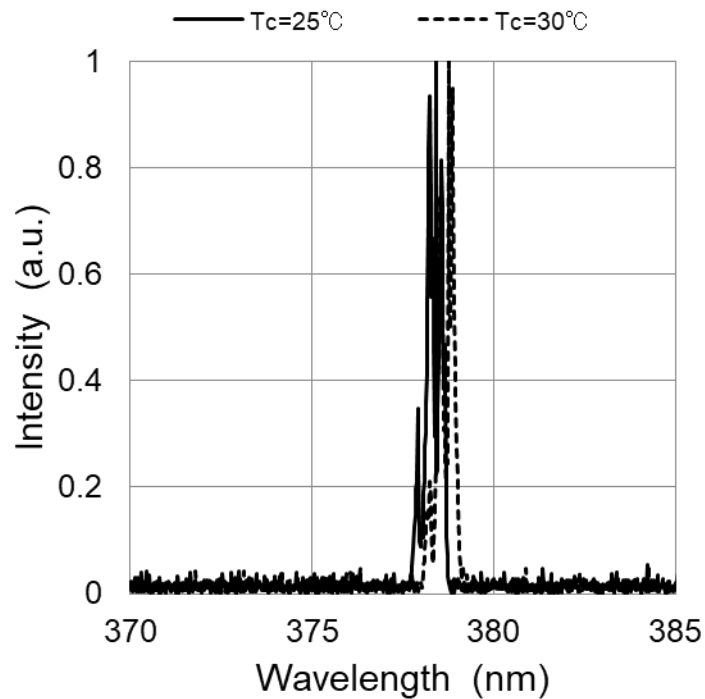


### Temperature and power dependence



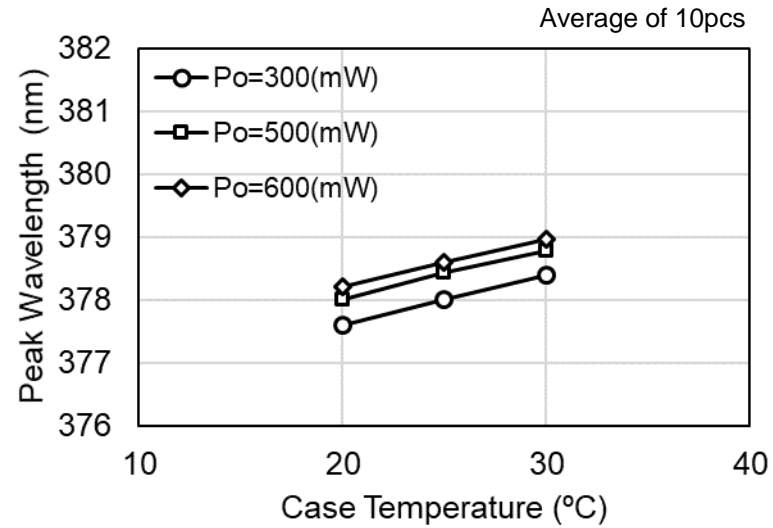
### Spectrum

[Conditions] CW, Po=500mW



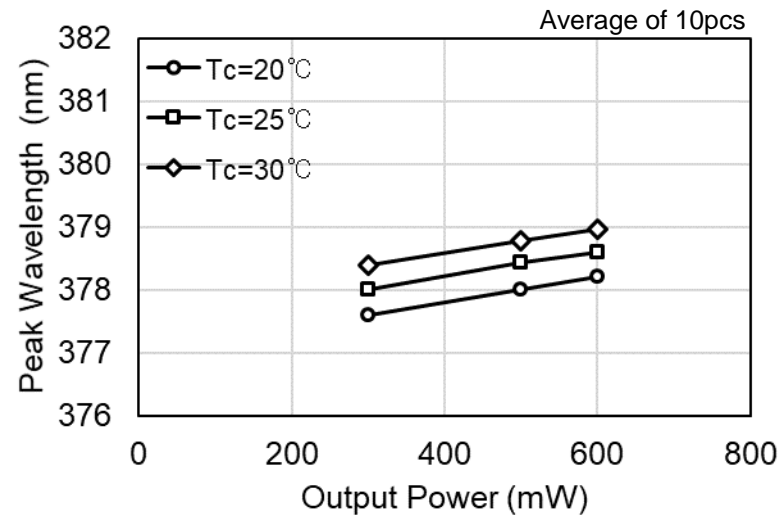
### Temperature and power dependence

[Conditions] CW



Po(mW)	$\Delta$ (nm/°C)
300	0.079
500	0.079
600	0.074

\*1 Between 20 and 30°C



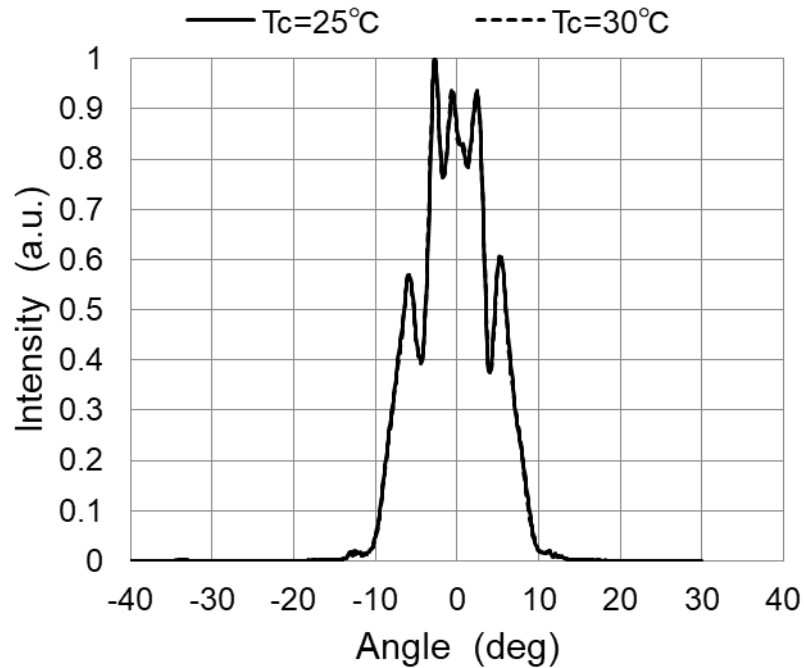
Tc(°C)	$\Delta$ (nm/mW)
20	0.0012
25	0.0012
30	0.0011

\*1 Between 300 and 600mW

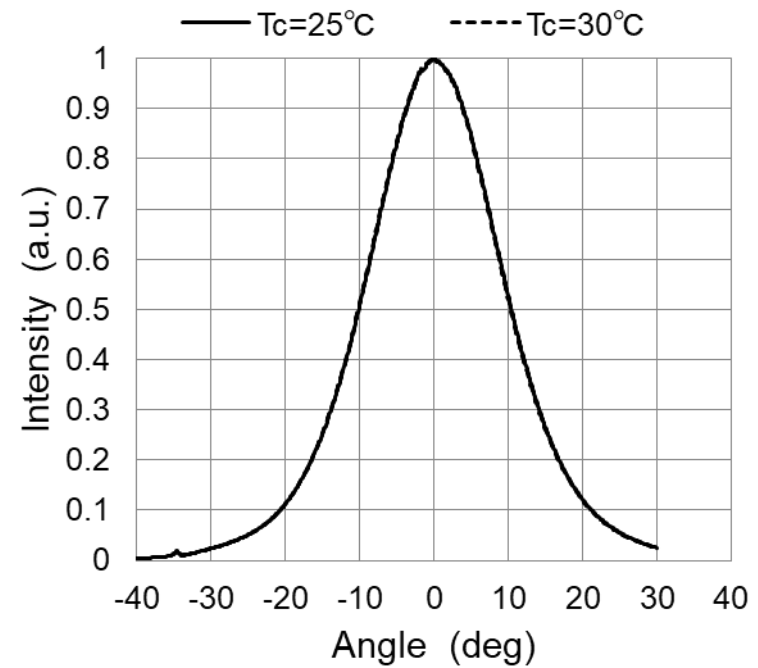
## ■ Far field pattern

[Conditions] CW, Po=500mW

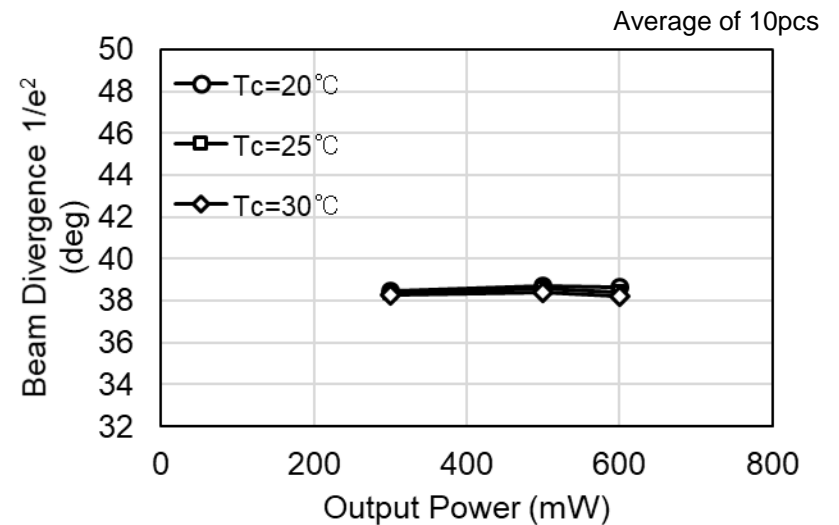
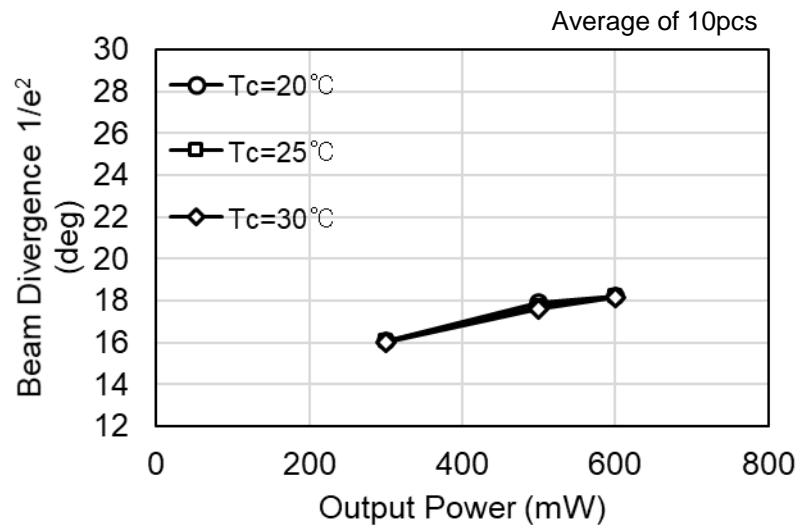
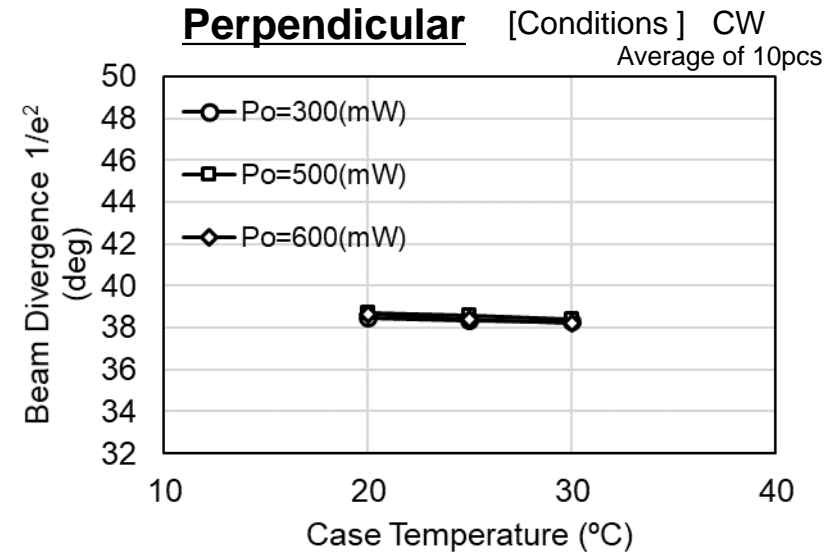
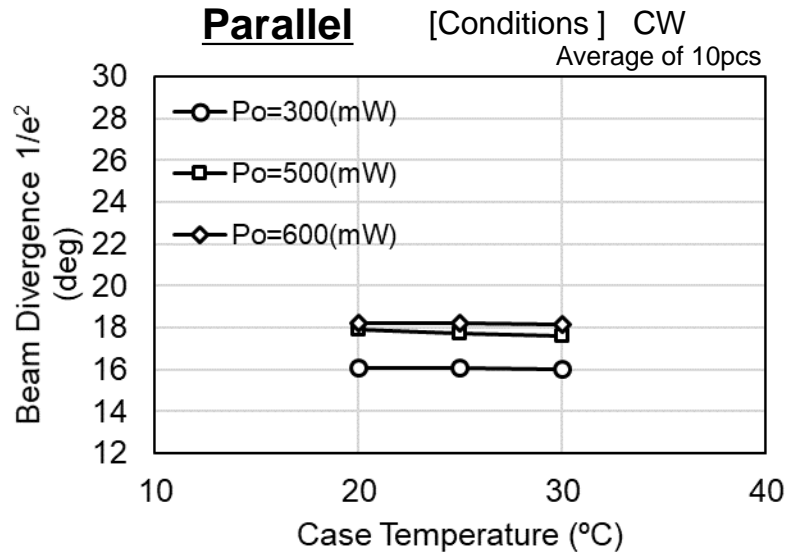
### Parallel



### Perpendicular

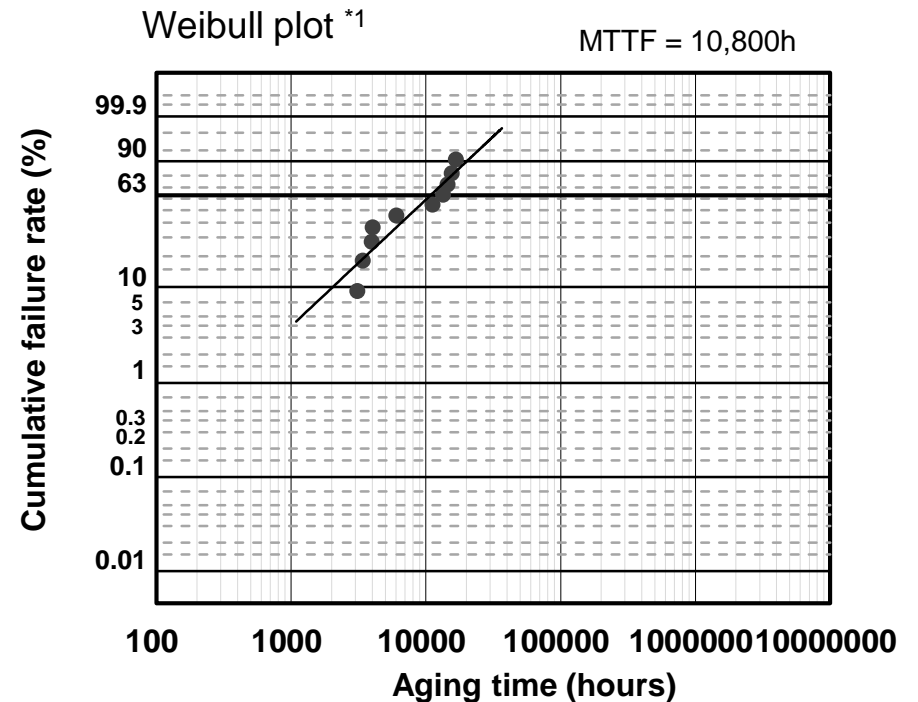
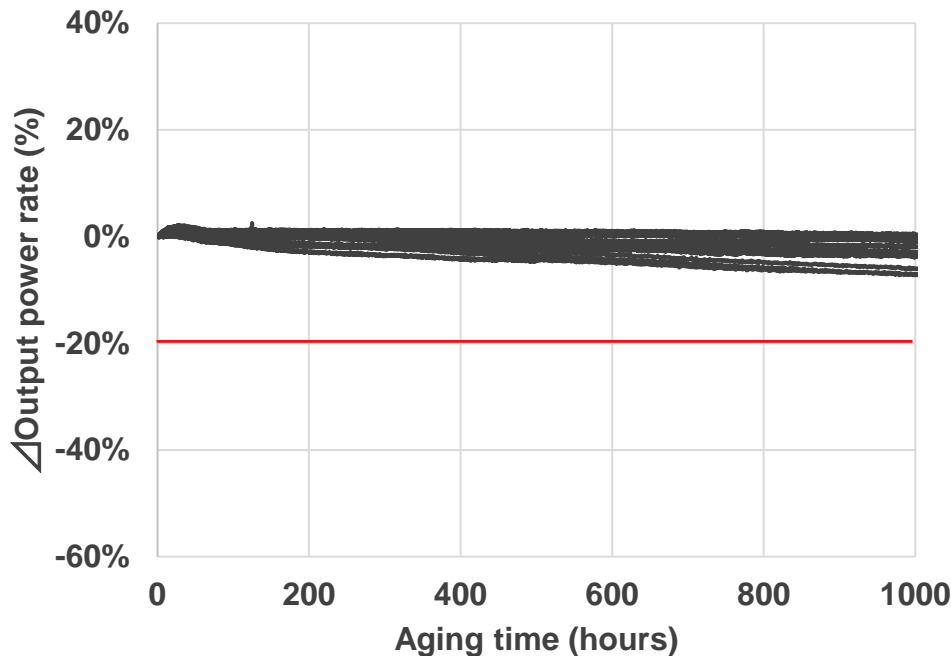


## Temperature and power dependence



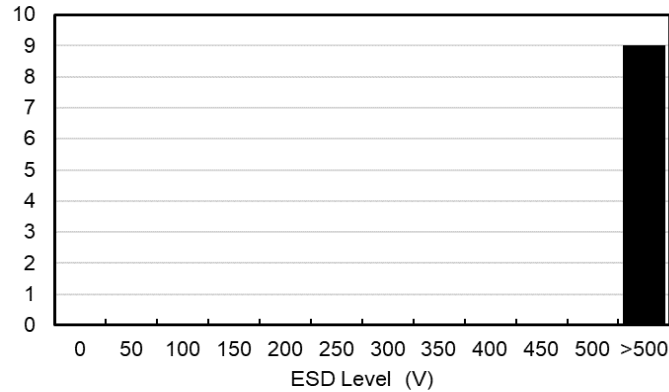
[Aging conditions ]

- CW, Tc=25°C, 10pcs
- ACC operation, initial output power P<sub>in</sub>= 500mW

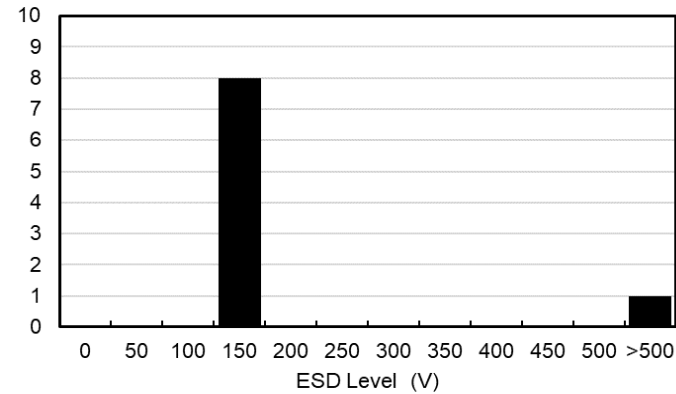


\*1Estimated by liner extrapolation of degradation rate.  
Failure criterion is defined as the time after which the output power drops to 80% of initial power.

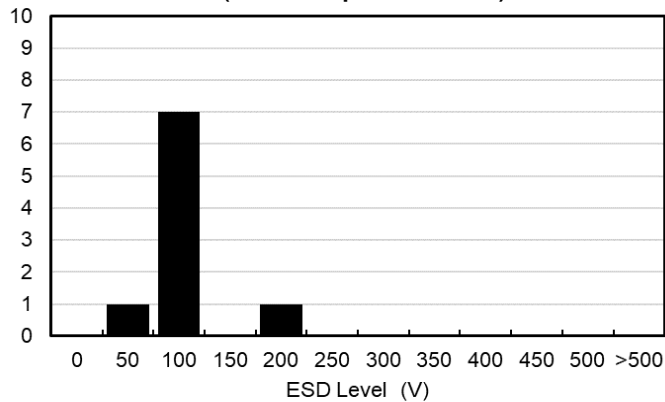
■ HBM+ (C=100pF, R=1.5kΩ)



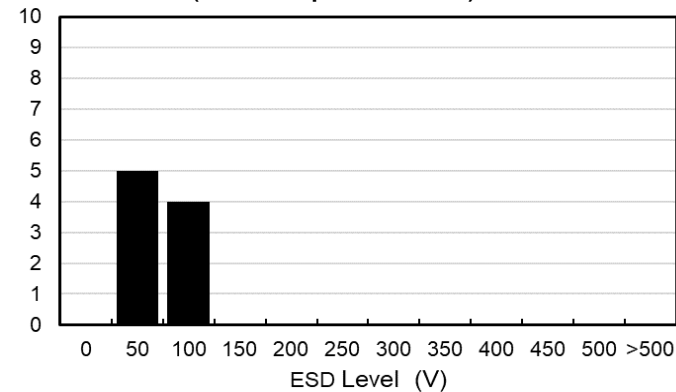
■ HBM- (C=100pF, R=1.5kΩ)



■ MM+ (C=200pF, R=0Ω)



■ MM- (C=200pF, R=0Ω)



Generally, laser diode is one of the most sensitive devices against ESD and Electrical surge from outside. Special cares are necessary to handle it. If electric pulses that may cause optical emission exceed the optical power specified as absolute maximum ratings is applied, the laser will be damaged by its own light intensity, resulting in the catastrophic degradation in a short time. Therefore, all possible measures against ESD and electrical surge are strongly required in design stage and production line.